

2. DIFFRACTION GEOMETRY AND ITS PRACTICAL REALIZATION

has been annealed. Then a model for the diffusion is assumed, and the coefficients are calculated. Using standard techniques, researchers are unable to detect the movement of an atom through a sample of like atoms. However, using single bilayers of amorphous ^{10}B and ^{11}B , it was shown (Smith, Hamilton, Fitzsimmons, Baker, Hubbard, Nastasi, Hirvonen & Zocco, 1992) through neutron-reflectivity measurements that the diffusion of boron in boron could be measured by studying the density profile (see Figs. 2.9.7.1 and 2.9.7.2) of one isotope in the other as a function of annealing time. Also, because of the sensitivity of the technique to the interfacial density profile, it was found that standard Fickian diffusion models could not explain the measured density profiles.

2.9.7.2. Magnetic multilayers

In order to understand interlayer coupling mechanisms, it is necessary to know what the magnetic superstructure is for a given nonmagnetic spacer layer thickness and/or applied field strength. Fig. 2.9.7.3 shows the spin-dependent reflectivities for a Co/Cu (111) multilayer along with the nuclear (Nb) and magnetic (Np) scattering-density profiles deduced from the data of Schreyer, Zeidler, Morawe, Metoki, Zabel, Ankner & Majkrzak (1993). In this specific case, the in-plane ferromag-

netic Co layers are themselves coupled ferromagnetically across the nonmagnetic Cu, all at a constant angle.

2.9.7.3. Hydrogenous materials

There are a substantial number of applications of neutron reflectometry in the study of hydrogenous films and multilayers, including diblock copolymer, surfactant, Langmuir–Blodgett, self-assembled monolayer, and lipid bilayer films. Reviews of the extensive research that has already been done have been written by Russell (1990) and Penfold & Thomas (1990). Only one specific example will be given here.

Fig. 2.9.7.4 shows neutron reflectivity data and the corresponding density profile for a Langmuir–Blodgett film composed of alternating bilayers of deuterated and hydrogenated stearic acid [after Wiesler, Feigin, Majkrzak, Ankner, Berzina & Troitsky (1995)]. Also shown in Fig. 2.9.7.4 is the scattering-density profile for the same sample as seen by X-rays. It is obvious that the X-rays are more sensitive to the high-Z barium in the head group, whereas the neutrons are especially good at distinguishing the degree of mixing between adjacent hydrogenated and deuterated hydrocarbon tails. This is a good example of the complementary nature of neutron and X-ray reflectivities.

References

2.1–2.2

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